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Fri, 22 Sep 2006, 12:20:34 PM EST

Search Query Display

Edit an existing query or compose a new query in the Search Query Display.

## Select a search number (#) to:

- Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- Delete a search
- · Run a search

Recent Search Queries		Results
<u>#1</u>	( ( first deposition <in>metadata ) <and> ( second deposition<in>metadata ) )</in></and></in>	1
<u>#2</u>	( ( first deposition <in>metadata ) <and> ( second deposition<in>metadata ) )</in></and></in>	1
<u>#3</u>	deposition layer	81
<u>#4</u>	((deposition layer) <and>(spacdr<in>metadata))</in></and>	0
<u>#5</u>	deposition layer	81
<u>#6</u>	((deposition layer) <and>(spacer<in>metadata))</in></and>	1
<u>#7</u>	deposition layer	81
<u>#8</u>	((deposition layer) <and>(flash memory<in>metadata))</in></and>	0
<u>#9</u>	deposition layer	81
<u>#10</u>	((deposition layer) <and>(split gate<in>metadata))</in></and>	0
<u>#11</u>	deposition layer	81
<u>#12</u>	((first layer <and>second layer)<and> ( semiconductor<in>metadata ) ) <and> (pyr &gt;= 1950 <and> pyr &lt;= 2004)</and></and></in></and></and>	233
<u>#13</u>	((((first layer <and>second layer)<and> ( semiconductor<in>metadata ) ) <and> (pyr &gt;= 1950 <and> pyr &lt;= 2004))<and>(thickness<in>metadata))</in></and></and></and></in></and></and>	21



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